


<b>Search Notes</b>  	<b>Application/Control No.</b>  10529608	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  Jan M Ludlow	<b>Art Unit</b>  1797

SEARCHED			
Class	Subclass	Date	Examiner
422	61, 100, 102	12/22/2008	
436	180	w/text	jml

SEARCH NOTES		
Search Notes	Date	Examiner
inventor search in eDAN	12/22/2008	jml

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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